# Generalization Theory for Deep Learning



### **Basic version: finite hypothesis class**

**Finite hypothesis class:** with probability  $1 - \delta$  over the choice of a training set of size *n*, for a bounded loss  $\ell$ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \ell(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[ \ell(f(x), y) \right] \right| = O\left(\sqrt{\frac{\log|\mathscr{F}| + \log 1/\delta}{n}}\right)$$

### **VC-Dimension**

**Motivation:** Do we need to consider **every** classifier in  $\mathcal{F}$ ? Intuitively, **pattern of classifications** on the training set should suffice. (Two predictors that predict identically on the training set should generalize similarly).

Let 
$$\mathscr{F} = \{f : \mathbb{R}^d \to \{+1, -1\}\}$$
 be a class of binary classifiers.

The growth function  $\Pi_{\mathscr{F}} : \mathbb{N} \to \mathbb{F}$  is defined as:

$$\Pi_{\mathscr{F}}(m) = \max_{(x_1, x_2, \dots, x_m)} \left| \left\{ (f(x_1), f(x_2), \dots, f(x_m)) \mid f \in \mathscr{F} \right\} \right|.$$

The VC dimension of  $\mathscr{F}$  is defined as: VCdim $(\mathscr{F}) = \max\{m : \Pi_{\mathscr{F}}(m) = 2^m\}$ .

# **VC-dimension Generalization bound**

**Theorem (Vapnik-Chervonenkis):** with probability  $1 - \delta$  over the choice of a training set, for a bounded loss  $\ell$ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{C}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[ \mathscr{C}(f(x), y) \right] \right| = O\left(\sqrt{\frac{\mathsf{VCdim}(\mathscr{F})\log n + \log 1/\delta}{n}}\right)$$

Examples:

- Linear functions: VC-dim = O(dimension)
- Neural network: VC-dimension of fully-connected net with width W and H layers is  $\Theta(WH)$  (Bartlett et al., '17).

# **Problems with VC-dimension bound**

- 1. In over-parameterized regime, bound >> 1.
- 2. Cannot explain the random noise phenomenon:
  - Neural networks that fit random labels and that fit true labels have the same VC-dimension.



# **PAC Bayesian Generalization Bounds**

**Setup:** Let *P* be a prior over function in class  $\mathcal{F}$ , let *Q* be the posterior (after algorithm's training).

**Theorem:** with probability  $1 - \delta$  over the choice of a training set, for a bounded loss  $\ell$ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{\ell}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[ \mathscr{\ell}(f(x), y) \right] \right| = O\left(\sqrt{\frac{KL(Q \mid |P) + \log 1/\delta}{n}}\right)$$

### **Rademacher Complexity**

Intuition: how well can a classifier class fit random noise?

(Empirical) Rademacher complexity: For a training set  $S = \{x_1, x_2, ..., x_n\}$ , and a class  $\mathscr{F}$ , denote:  $\hat{R}_n(S) = \mathbb{E}_{\sigma} \sup_{f \in \mathscr{F}} \sum_{i=1}^n \sigma_i f(x_i)$ . where  $\sigma_i \sim \text{Unif}\{+1, -1\}$  (Rademacher R.V.).

(Population) Rademacher complexity:

$$R_n = \mathbb{E}_S \left[ \hat{R}_n(s) \right].$$

#### **Rademacher Complexity Generalization Bound**

**Theorem:** with probability  $1 - \delta$  over the choice of a training set, for a bounded loss  $\ell$ , we have

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{E}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[ \mathscr{E}(f(x), y) \right] \right| = O\left(\frac{\hat{R}_n}{n} + \sqrt{\frac{\log 1/\delta}{n}}\right)$$

#### and

$$\sup_{f \in \mathscr{F}} \left| \frac{1}{n} \sum_{i=1}^{n} \mathscr{\ell}(f(x_i), y_i) - \mathbb{E}_{(x, y) \sim D} \left[ \mathscr{\ell}(f(x), y) \right] \right| = O\left(\frac{R_n}{n} + \sqrt{\frac{\log 1/\delta}{n}}\right)$$

# **Kernel generalization bound**

Use Rademacher complexity theory, we can obtain a generalization bound  $O(\sqrt{y^{\top}(H^*)^{-1}y/n})$  where  $y \in \mathbb{R}^n$  are n labels, and  $H^* \in \mathbb{R}^{n \times n}$  is the kernel (e.g., NTK) matrix.



#### Norm-based Rademacher complexity bound

**Theorem:** If the activation function is  $\sigma$  is  $\rho$ -Lipschitz. Let  $\mathscr{F} = \{x \mapsto W_{H+1}\sigma(W_h\sigma(\cdots\sigma(W_1x)\cdots), \|W_h^T\|_{1,\infty} \leq B \forall h \in [H]\}$ then  $R_n(\mathscr{S}) \leq \|X^\top\|_{2,\infty}(2\rho B)^{H+1}\sqrt{2\ln d}$  where  $X = [x_1, \dots, x_n] \in \mathbb{R}^{d \times n}$  is the input data matrix.

# **Comments on generalization bounds**

- When plugged in real values, the bounds are rarely non-trivial (i.e., smaller than 1)
- "Fantastic Generalization Measures and Where to Find them" by Jiang et al. '19 : large-scale investigation of the correlation of extant generalization measures with true generalization.



Image credits to Andrej Risteski

# **Comments on generalization bounds**

- Uniform convergence may be unable to explain generalization of deep learning [Nagarajan and Kolter, '19]
  - Uniform convergence: a bound for all  $f\in \mathscr{F}$
  - Exists example that 1) can generalize, 2) uniform convergence fails.

- Rates:
  - Most bounds:  $1/\sqrt{n}$ .
  - Local Rademacher complexity: 1/n.

• For approximation and optimization, neural network has no advantage over kernel. Why NN gives better performance: generalization.

- [Allen-Zhu and Li '20] Construct a class of functions  $\mathscr{F}$  such that y = f(x) for some  $f \in \mathscr{F}$ :
  - no kernel is sample-efficient;
  - Exists a neural network that is sample-efficient.



Belkin, Hsu, Ma, Mandal '18

- There are cases where the model gets bigger, yet the (test!) loss goes down, sometimes even lower than in the classical "under-parameterized" regime.
- Complexity: number of parameters.

Widespread phenomenon, across architectures (Nakkiran et al. '19):



(a) **CIFAR-100.** There is a peak in test error even with no label noise.



(b) **CIFAR-10.** There is a "plateau" in test error around the interpolation point with no label noise, which develops into a peak for added label noise.

Widespread phenomenon, across architectures (Nakkiran et al. '19):



Widespread phenomenon, also in kernels (can be formally proved in some concrete settings [Mei and Montanari '20]), random forests, etc.



Also in other quantities such as train time, dataset, etc (Nakkiran et al. '19):



Figure 2: Left: Test error as a function of model size and train epochs. The horizontal line corresponds to model-wise double descent-varying model size while training for as long as possible. The vertical line corresponds to epoch-wise double descent, with test error undergoing double-descent as train time increases. **Right** Train error of the corresponding models. All models are Resnet18s trained on CIFAR-10 with 15% label noise, data-augmentation, and Adam for up to 4K epochs.

Optimal regularization can mitigate double descent [Nakkiran et al. '21]:

0.9 Unregularized  $\lambda = 0.0005$  $\lambda = 0.001$  $\lambda = 0.003$ 0.8  $-\lambda = 0.005$  $\rightarrow$   $\lambda = 0.01$ Optimally Regularized Test Error €0.7 0.5 0.4 10 20 30 40 0 50 60 CNN Model Size (width)

Effect of Regularization: CNNs on CIFAR-100

# Optimal regularization can mitigate double descent [Nakkiran et al. '21]:





a) Test Classification Error vs. Number of Trainng Samples.

(b) Test Classification Error vs. Model Size (Number of Random Features).

# **Implicit Regularization**

Different optimization algorithm

#### ➔ Different bias in optimum reached

➔ Different Inductive bias

➔ Different generalization properties



# **Implicit Bias**

Margin:

- Linear predictors:
  - Gradient descent, mirror descent, natural gradient descent, steepest descent, etc maximize margins with respect to different norms.
- Non-linear:
  - Gradient descent maximizes margin for homogeneous neural networks.
  - Low-rank matrix sensing: gradient descent finds a low-rank solution.